[Title]			[Instructor]				
	Adv	anced Instrumental Analysis IA	Jı	Junji Yamanaka			
[Code]	[Credits]	[Program]	[Semester] [Hours] [Language of instruction]				
320110A GTI501	1	For All Programs of "Division of Engineering"	Intensive	/	English/ Japanese		
[Outline an	d purpose]						
We will lear	rn practical	knowledge how to operate Transmission Electron	Microscopes (	ГЕМ).			
[Objectives]							
,		out basic mechanical structure of TEM. w to operate the TEM in the "Center for Instrumen"	tal Analysis."				
[Requireme	ents]						
<ol> <li>(Mandatory): Completion of undergraduate course covering basic physics.</li> <li>(Mandatory): Completion of undergraduate course covering basic chemistry.</li> <li>(Mandatory): Completion of undergraduate course of laboratory class about science/engineering.</li> <li>(Mandatory): Your supervisor must agree that you will use the TEMs in the "Center for Instrumental Analysis."</li> <li>(Optional): If you have a specific purpose to use TEM for your thesis, it will be desirable.</li> </ol>							
[Evaluation	n]						
Quizzes and Practical SI		ts: 50% nation: 50%					
[Textbooks]							
[References	5]						
[Schedule]							
<ol> <li>What can we do using Transmission Electron Microscope (TEM)?</li> <li>Principle of Transmission Electron Microscopy.</li> <li>Basic Mechanical Structure of TEM.</li> <li>How to check the condition of TEM in the "Center for Instrumental Analysis."</li> <li>Specimen Preparation and TEM Operation. Part 1.</li> <li>Specimen preparation and TEM operation. Part 2.</li> <li>Specimen preparation and TEM operation. Part 3.</li> <li>Data Analysis. Part 1.</li> <li>Data Analysis. Part 2.</li> </ol>							
*: It is requ	<ul> <li>10. Discussion and Summary.</li> <li>*: It is required to receive the credit of this class in advance if you would like to use the TEMs in the "Center for Instrumental Analysis."</li> </ul>						
	*: If you already have the credit of the "Instrumental Analysis 1A", which is for undergraduate, you don't have to receive this credit to use the TEMs in the "Center for Instrumental Analysis."						
		tions how to prepare the TEM specimens and how earned precisely, at the beginning of this class.	v to operate t	he TEM. W	e can discuss		

		[Title]	[Instructor]				
	Advar	aced Instrumental Analysis IB	Junji Yamanaka				
[Code]	[Credits]	[Program]	[Semester] [Hours] [Langua instruction				
GTI502	1	For All Programs of "Division of Engineering"	, Intensive Course	/	English⁄ Japanese		
[Outline an	d purpose]				•		
We will lear	We will learn practical knowledge how to operate Scanning Electron Microscopes (SEM).						
[Objectives]							
,		out basic mechanical structure of SEM. w to operate the SEM in the "Center for Instrum	ental Analysis."				
[Requireme	ents]						
<ol> <li>(Mandatory): Completion of undergraduate course covering basic physics.</li> <li>(Mandatory): Completion of undergraduate course covering basic chemistry.</li> <li>(Mandatory): Completion of undergraduate course of laboratory class about science/engineering.</li> <li>(Mandatory): Your supervisor must agree that you will use the SEMs in the "Center for Instrumental Analysis."</li> <li>(Optional): If you have a specific purpose to use SEM for your thesis, it will be desirable.</li> </ol>							
[Evaluation	n]						
Quizzes and Practical Sl		ts: 50% nation: 50%					
[Textbooks]							
[References	5]						
[Schedule]							
		ng Scanning Electron Microscope (SEM)?					
		ng Electron Microscopy. tructure of SEM.					
		ndition of SEM in the "Center for Instrumental .	Analysis."				
		on and SEM Operation. Part 1.					
		on and SEM operation. Part 2.					
		on and SEM operation. Part 3.					
8. Data Ana 9. Data Ana	-						
10. Discuss	-						
*: It is required to receive the credit of this class in advance if you would like to use the SEMs in the "Center for Instrumental Analysis."							
*: If you already have the credit of the "Instrumental Analysis 1B", which is for undergraduate, you don't have to receive this credit to use the SEMs in the "Center for Instrumental Analysis."							
		tions how to prepare the SEM specimens and earned precisely, at the beginning of this class.	how to operate t	he SEM. W	e can discuss		

[Title]			[Instructor]			
	Advar	aced Instrumental Analysis IC	Isao Tanaka / Satoshi Watauchi / Yoichi Nabetani			
[Code]	[Credits]	[Program]	[Seme	ester]	[Hours]	[Language of instruction]
GTI503	1	For All Programs of "Division of Engineering	" Inten	sive	/	English/ Japanese
[Outline an	d purpose]					
spectroscop After unde	e. EPMA erstanding	e analyzer (EPMA) is composed of a scan is useful for compositional analysis of solid surf the principle and feature of EPMA, the meas litative analysis and quantitative analysis is ac	ace with m urement te	icrome	eter to centi	meter size.
[Objectives]						
2. Masterin 3. Masterin	g measurei g measurei	ciple and feature of EPMA ment technique of electron microscope observati ment technique of X-ray qualitative analysis ment technique of X-ray quantitative analysis	on			
[Requireme	ents]					
Understand	ling X-ray o	diffraction method and spectroscopy				
[Evaluation	-					
		omework: 50%				
practice ski	II · 30%					
[Textbooks]						
[References	]					
[Schedule]						
1. Purpose	of measure	ment				
-		neasurement				
3. Principle 4. Maintena		-				
		ning electron microscope (sample preparation a	nd microsco	ope op	eration)	
		qualitative analysis				
		quantitative analysis ic)				
	8. Data analysis I (basic) 9. Data analysis II (application)					
10. Summa	ry					
	*1 You should get 1 credit for this class to use EPMA. **2 If you have already gotten 1 credit for this class in undergraduate, you do not take this class.					

[Title]				[Instructor]				
	Adv	anced Instrumental Analysis ID		Tetsuya Sato				
[Code]	[Credits]	[Program]	[Semester] [Hours] [Language instruction					
GTI504	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese			
	[Outline and purpose] X-ray photoelectron spectroscopy (XPS) is useful for chemical characterization of thin films and surfaces							
because it if XPS is true than $\sim 15$	is capable e surface a Å deep. A	of readily providing information on the nature of nalytical techniques, since the detection electrons fter understanding the principle and measurement ysis is acquired.	chemical bor s are emitted	nding and v from surfa	alence states. ce layers less			
[Objectives]								
2. Masterin	g measure	ciple of X-ray photoelectron spectroscopy. ment technique of X-ray photoelectron spectrometer of XPS spectra.	r.					
[Requireme								
Understand	ling the fur	ndamental of ultrahigh vacuum and electron spectr	oscopy techni	ques.				
[Evaluation	-							
brief exami practice ski		omework: 50%						
[Textbooks]								
[References	5]							
[Schedule]								
[Schedule]         1. Purpose of measurement         2. Principle of XPS measurement         3. Principle of XPS analyzer         4. Maintenance of XPS         5. Operation of XPS equipment (sample preparation, )         6. Operation of sputter depth profiling.         7. Data analysis I (Qualitative analysis)         8. Data analysis II (Quantitative analysis)         9. Summary								
*1 You should get 1 credit for this class to use XPS. **2 If you have already gotten 1 credit for this class in undergraduate, you do not take this class.								

[Title]			[Instructor]			
	Adva	anced Instrumental Analysis IG	Tsu	Tsutomu Muranaka		
[Code]	[Credits]	[Program]	[Semester] [Hours] [Language instruction			
GTI507	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese	
[Outline an	d purpose]					
Liquid nitrogen is nitrogen in a liquid state at an extremely low temperature (< 77K). The extreme cold of liquid nitrogen makes handling it very dangerous because it can cause very serious burns that irreparably destroy skin or eyes. Professionals who use it must undergo training to properly learn about its reactivity and thus take appropriate precautions. Liquid nitrogen is stored, shipped and handled in several types of containers, depending upon the quantity required by the user. After understanding the feature of liquid nitrogen and associated hazards, the safe handling of liquid nitrogen (and container) is shown.						
[Objectives]						
1. Understa 2. Safe han	nding feat dling of liqu	ure of liquid nitrogen and associated hazards uid nitrogen and equipment nitrogen from primary container				
[Requireme	nts]					
Basic under	standing o	f chemistry and physics				
[Evaluation	.]					
brief exami practice ski		omework: 50%				
[Textbooks]						
[References	]					
[Schedule]						
01. User guidance of "Center for Instrumental Analysis"         02. Outline and purpose         03. Characteristics of liquid nitrogen and associated hazards         04. Handling liquid nitrogen and containers         05. Transferring liquid nitrogen from primary container (Lecture)         06. Transferring liquid nitrogen from primary container (Training)         07. Summary						
		edit for this class to use liquid nitrogen. y gotten 1 credit for this class in undergraduate, yo	u do not take	this class.		

	[Title]	[Instructor]				
Advanced Instrumental Analysis IIC			Tetsuo Kuwabara/ Susumu Kokubo /			
				Masayo Katsumata		
[Code]	[Credits]	[Program]	[Semester]	[Hours]	[Language of instruction]	
GTI510	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese	
[Outline an	d purpose]					
organic con	npounds. It	esonance spectrometry (NMR) is a typical analytic determines the physical and chemical properties analytical technique of NMR are lectured and trained	of atom or n	olecules.	al analysis of The principle,	
[Objectives]						
		ciple and feature of NMR				
		technique of NMR				
		ciple and feature of NMR technique of NMR				
[Requireme	ents]					
		ganic compounds and NMR spectroscopy				
[Evaluation	ı]					
Participation Practice ski						
[Textbooks]						
None						
[References						
None						
[Schedule]						
1. Principle	of NMR					
2. Instrume		NMR				
3. Analytica						
	<ol> <li>Sample preparation, operation and data analysis of NMR</li> <li>Principle of NMR</li> </ol>					
6. Instrume		NMR				
	7. Analytical procedure of NMR					
	8. Sample preparation, operation and data analysis of NMR					
9. Applicati 10. Summa						
10. Dumma	±J					

[Title]			[Instructor]				
Advanced Instrumental Analysis IIIA				Masashi Hisamoto / Makoto Obata			
[Code]	[Credits]	[Program]	[Semester] [Hours] [Language instruction				
GTI511	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese		
[Outline an	d purpose]						
	The purpose of this course is to learn the principles and practical methods of LC-MS and/or elemental analysis (carbon, hydrogen, and nitrogen). Students must take at least one analytical technique from each lecture.						
[Objectives]							
-		nd data analysis methods used in LC-MS and/or ele	emental analy	rsis.			
[Requireme	ents]						
Good under	standing or rstandings	f basic organic chemistry is required in all courses of liquid and gas chromatography are beneficial	in LC-MS a	nd/or eleme	ntal analysis		
[Basis of Ev	valuation]						
Reports (30 Practical E							
[Textbooks]							
Title: 役にご							
		会 有機微量分析研究懇談会					
Publisher: ISBN: 978-		5-3					
[References	5]						
Not specifie	ed						
[Schedule]							
1. Guidan	ce						
	les of meas						
		umentation inspection of equipment					
		surement 1					
6. Instrun							
7. Instrumental measurement 3							
8. Data analysis 1 9. Data analysis 2							
	<ol> <li>Data analysis 2</li> <li>Review</li> </ol>						
<ul> <li>10. Review</li> <li>*1 You should take at least one analytical technique course from each lecture to get 1 credit for this class.</li> <li>**2 If you have already gotten 1 credit for this class in undergraduate, you do not take this class.</li> <li>***3 If you are going to use LC-MS or elemental analysis, you should take all corresponding courses to get user</li> </ul>							

license.

[Title]				[Instructor]		
Advanced Instrumental Analysis IIIB			Fı	Futaba Kazama / Ikuo Ueta		
[Code]	[Credits]	[Program]	[Semester]	[Hours]	[Language of instruction]	
GTI512	1	For All Programs of "Division of Engineering"	Intensive	/	English/ Japanese	
[Outline an	1 1					
Theory and	application	n of GC-MS for analyzing organic compounds.				
[Objectives]	]					
		ciple of GC-MS. ve analysis by GC-MS.				
[Requireme	ents]					
		ple of gas chromatography				
	1					
[Evaluation Practical S		nation: 100%				
110000000						
[Textbooks]						
[References	5]					
[Schedule]						
		easurement.				
-		measurement. ple of GC-MS.				
4 Maintena	nce and ins	spection of GC-MS.				
5. Practice		eparation). ment method).				
		nent method).				
	8. Data analysis (basic).					
	9. Data analysis (application). 10. Summary.					
	-	edit for this class to use GC-MS.				

[Title]			[Instructor]			
	Adva	nced Instrumental Analysis IIIC	Susumu Kawakubo / Yasutada Suzuki / Masayo Katsumata			
[Code]	[Credits]	[Program]	[Semester] [Hours] [Langua instruc			
GTI513	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese	
[Outline and purpose] X-ray fluorescence Spectrometry (XRFS) and inductively-coupled plasma atomic emission spectrometry (ICP-AES) are typical analytical methods for elemental analysis for solid and liquid samples, respectively. The principle, feature and practical analytical technique of XRFS and ICP-AES are lectured and trained in this lecture.						
[Objectives]						
<ol> <li>Understa</li> <li>Training</li> <li>Understa</li> </ol>	anding prin analytical anding prin	ciple and feature of XRFS technique of XRFS ciple and feature of ICP-AES technique of ICP-AES				
[Requireme	ents]					
		ray fluorescence and emission spectroscopy				
[Evaluation	1]					
report or m practice ski		mination : 40%				
[Textbooks]						
None						
References	]					
None	-					
[a ]						
[Schedule]	A 115					
<ol> <li>5. Principle</li> <li>6. Instrume</li> <li>7. Analytica</li> </ol>	entation of a al procedur preparation of ICP-AE entation of al procedur preparation ons	e of XRFS , operation and data analysis of XRFS S				

		[Title]		[Instructor	·]	
Advanced Instrumental Analysis IIID			Makoto Obata			
[Code]	[Credits]	[Program]	[Semester] [Hours] [Langua instruc			
GTI514	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese	
[Outline an	nd purpose]		1			
The purpo Spectrosco		course is to learn the principles and practical m	nethods of Fou	urier Trans	form Infrared	
[Objectives	<u></u> ]					
1. To und	erstand the	principle Infrared spectrometry spect of FTIR operation				
[Requirem	entsl					
*		ed spectrometry				
0	0					
[Evaluatio	n]					
		e class (30%)				
Practice sk	till (70%)					
[Textbooks	]					
[Reference	s]					
		vtical Chemistry (6th Ed)				
II Instrum	ental Analy	sis (Japanese TR), Maruzen				
[Schedule]						
1. Object	of IR measu					
	ole of IR me					
	ole of FTIR i and mainte	instrument nance of FTIR instrument				
		ement 1 (sample preparation and practice)				
6. Metho	d of measur	ement 2 (sample preparation and practice)				
		ement 3 (sample preparation and practice)				
	lata analysi ced data ana					
10. Summ						

[Title]			[Instructor]			
Advanced Instrumental Analysis IIIE				Tetsuya Sato / Keisuke Arimoto		
[Code]	[Credits]	[Program]	[Semester] [Hours] [Language instructio			
GTI515	1	For All Programs of "Division of Engineering"	Intensive	/	Japanese	
[Outline an	d purpose]					
Laser Raman Scattering Spectroscopy (LRSS) is used to characterize materials and crystallographic orientation of a sample. LRSS offers several advantages for microscopic analysis. Since it is a scattering technique, specimens do not need to be fixed or sectioned. Raman spectra can be collected from a very small volume (< 1 $\mu$ m in diameter); these spectra allow the identification of species present in that volume. After understanding the principle and measurement technique of LRSS, qualitative analysis and quantitative analysis is acquired.						
[Objectives]						
2. Masterin 3. Masterin	<ol> <li>Understanding principle and feature of LRSS</li> <li>Mastering measurement technique of LRSS qualitative analysis</li> <li>Mastering measurement technique of LRSS qualitative analysis</li> </ol>					
[Requireme	ents]					
Understand	ling the fur	ndamental of Raman effect, laser, light scattering.				
[Evaluation	l]					
brief exami practice ski		omework: 50%				
[Textbooks]						
[References						
[Schedule]						
<ol> <li>3. Principle</li> <li>4. Maintena</li> <li>5. Operation</li> <li>6. Operation</li> </ol>	of LRSS m of LRSS a ance of LRS n of LRSS o n of LRSS o lysis I (bas lysis II (ap	neasurement nalyzer SS equipment (sample preparation, ) qualitative analysis quantitative analysis ic)				
	-	edit for this class to use LRSS. y gotten 1 credit for this class in undergraduate, yo	u do not take	this class.		